

0.1-10 MeV Neutron Soft Error Rate in Accelerator and Atmospheric Environments

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on behalf of the R2E project

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<https://indico.cern.ch/event/971222/>



Introduction: radiations in the LHC

Radiation sources



Collision debris

Residual gas

Collimators

Radiation environment mainly composed of **neutrons** in

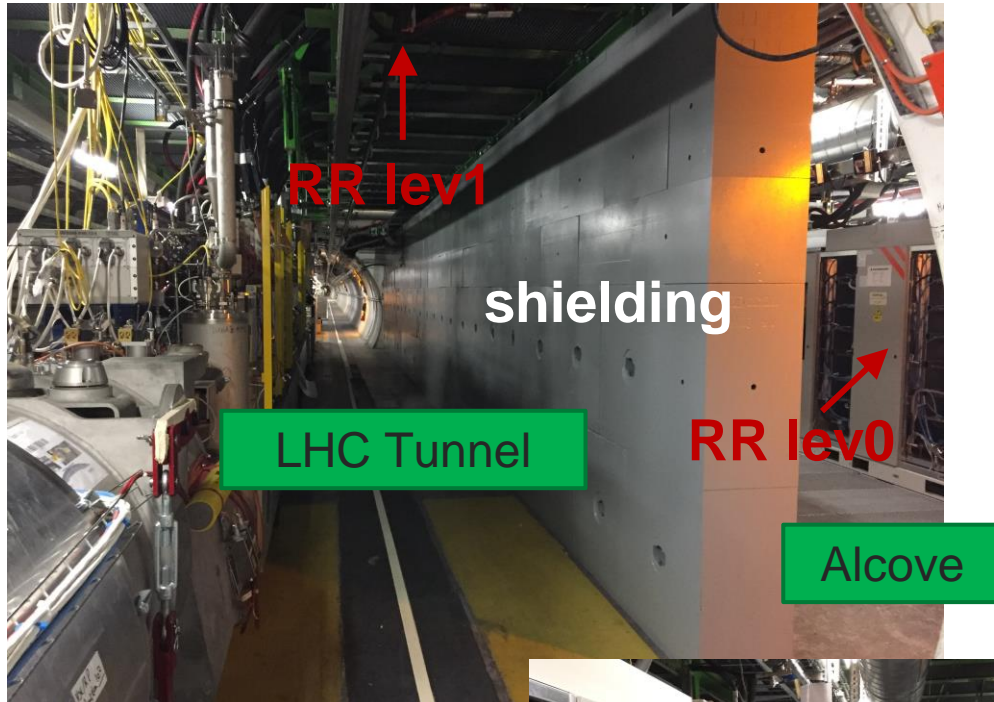
Tunnel

Shielded alcoves

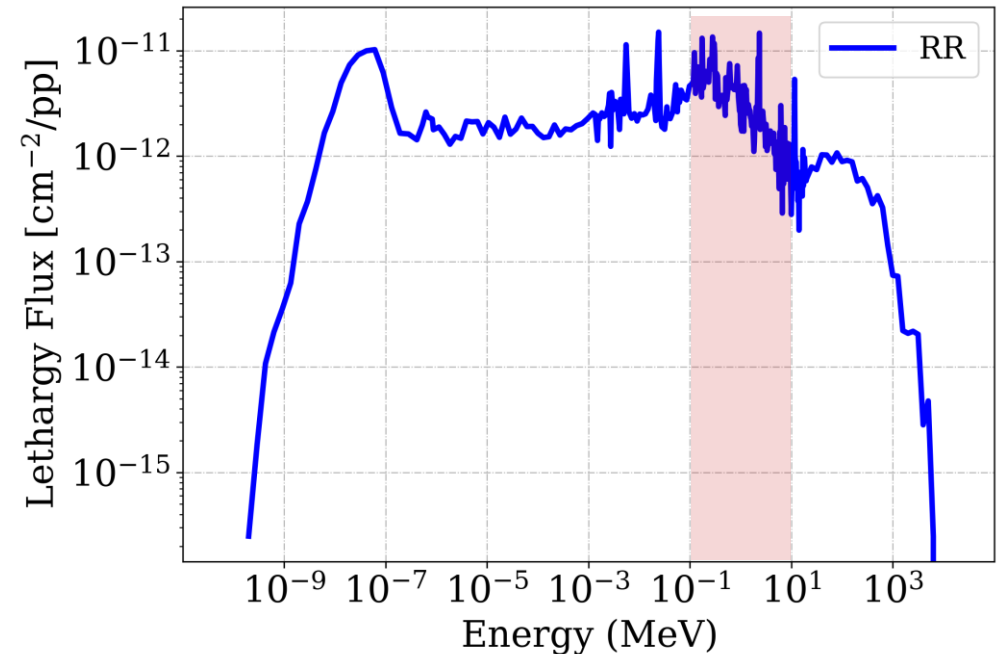
A large number of electronics (mainly **COTS**) operate near the accelerator and are exposed to **radiation inducing SEEs**



Example - Neutron spectrum in the RR alcove



From FLUKA Monte Carlo simulations



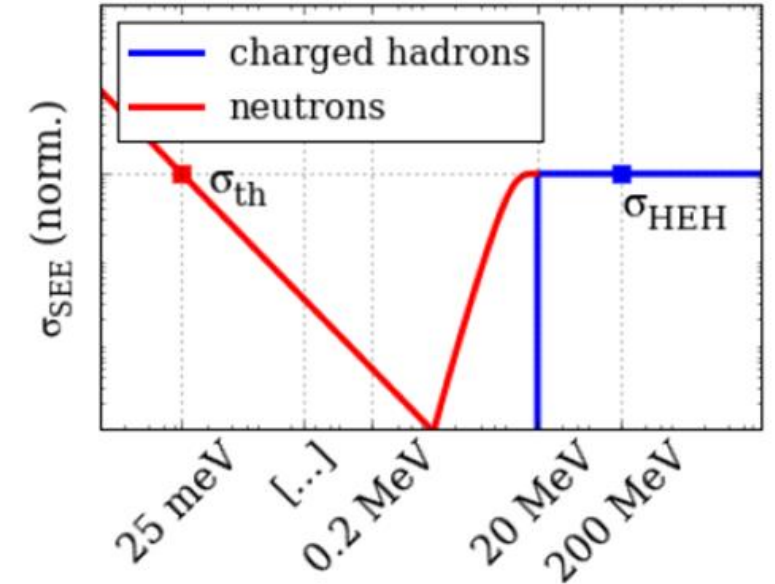
- **Lightly shielded alcove**, 40 cm cast iron/concrete
- Up to **90%** of the HEH (hadrons > 20 MeV) spectrum composed of **neutrons**
- Shielding reduces HEH radiation levels from **$\sim 10^{10}$** (tunnel) to **$\sim 10^9$ HEH/cm²/year** (HL-LHC)

SEEs: response function

Intermediate energy neutrons

from 0.2 to 20 MeV, the device (SRAM) cross section is strongly energy dependent

$$\varphi_{HEHeq} = \underbrace{\int_{0.2\text{MeV}}^{20\text{MeV}} w(E) \frac{d\varphi_n(E)}{dE} dE}_{\text{intermediate energy neutrons}} + \int_{20\text{MeV}}^{+\infty} \frac{d\varphi_{HEH}(E)}{dE} dE$$



- ➔ Intermediate energy neutrons - major concern with scaling of technology
- ➔ Memory response $w(E)$ so far considered from 400 nm Toshiba SRAM

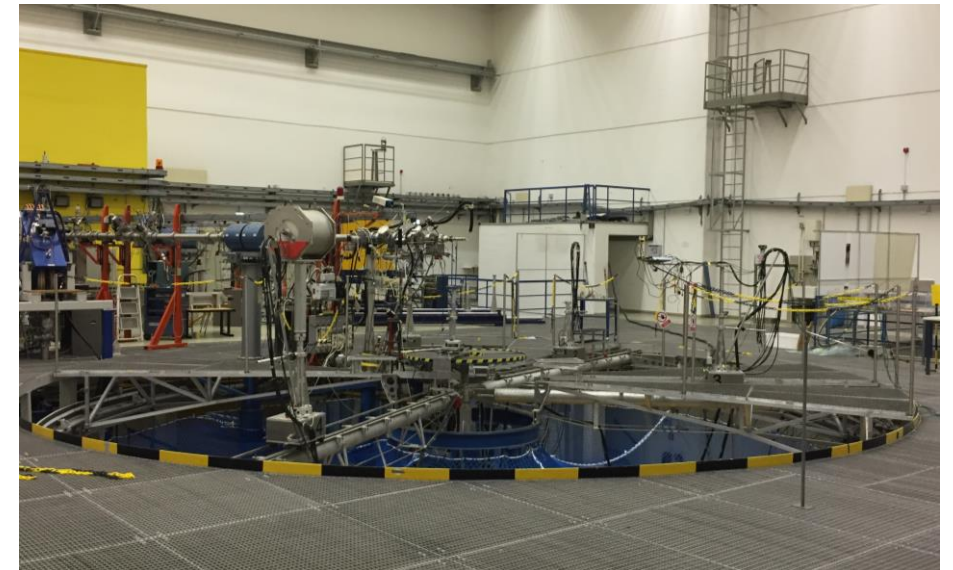
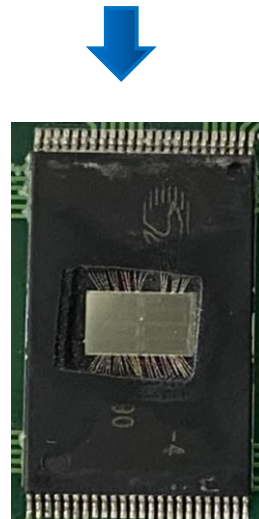
Components – Neutron test facilities

- Test performed at **PTB** (Germany) and **FNG** (Italy)
- Mono-energetic neutron irradiations, from **0.144 to 17 MeV**

- ➔ SRAMs of different technologies
- ➔ SEU tests with **package** and **delidded**

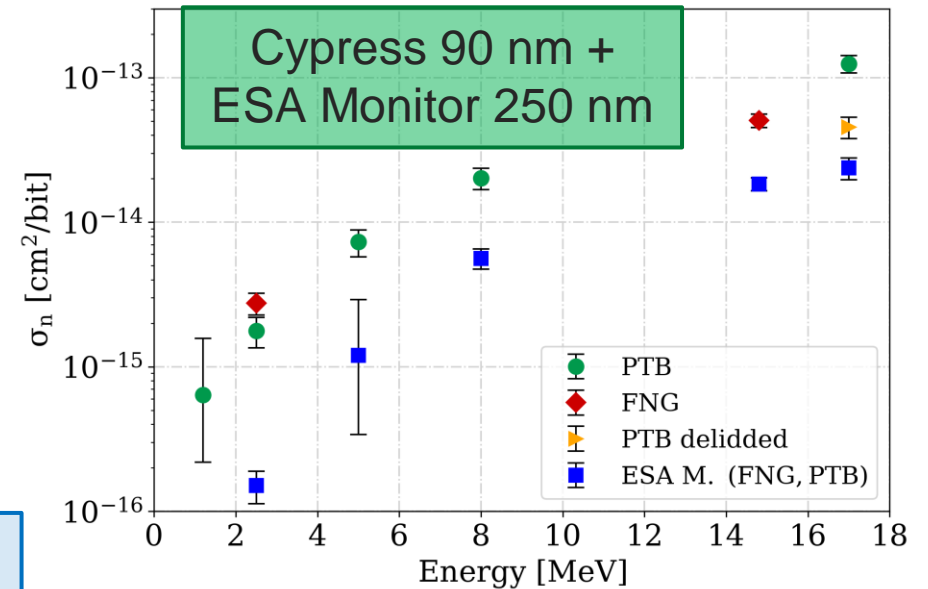
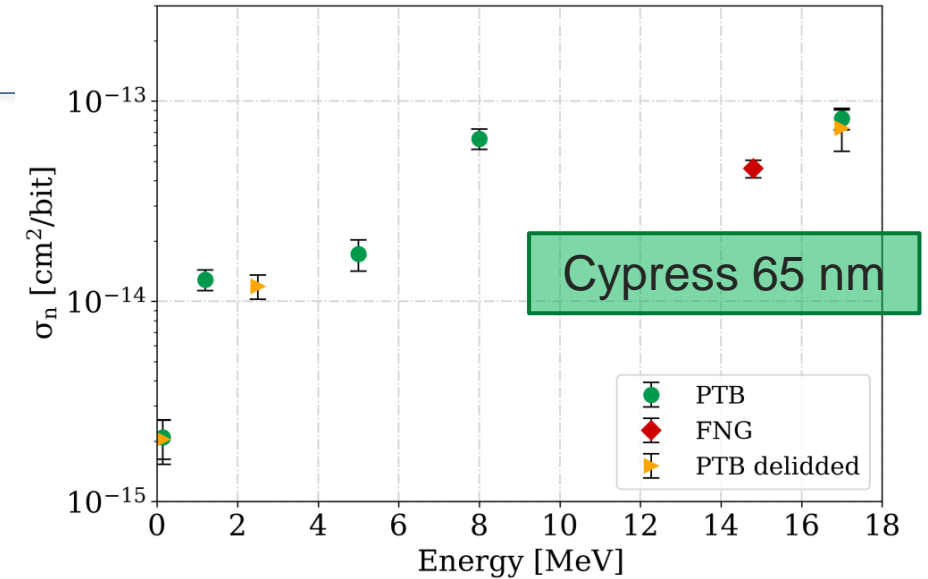
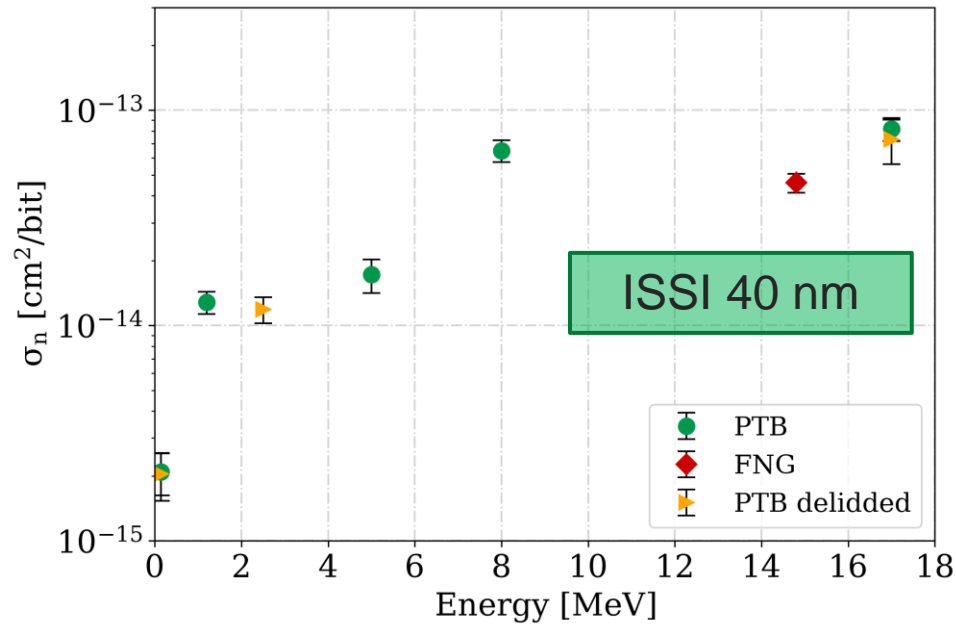
Memory	Tech [nm]	Size [Mbit]
ISSI	40	32
Cypress	65	16
Cypress	90	8
ESA Monitor	250	16

Facility	E_n [MeV]	Reaction	E_{proj} [keV]
PTB	0.144	Li(p,n)	1943
PTB	1.2	T(p,n)	2047
PTB	2.5	T(p,n)	3356
FNG	2.5	D(d,n)	300
PTB	5	D(d,n)	2406
PTB	8	D(d,n)	2524
FNG	14.8	T(d,n)	300
PTB	17	T(d,n)	1264



PTB irradiation room

SRAM neutron cross sections



40 and 65 nm SRAMs

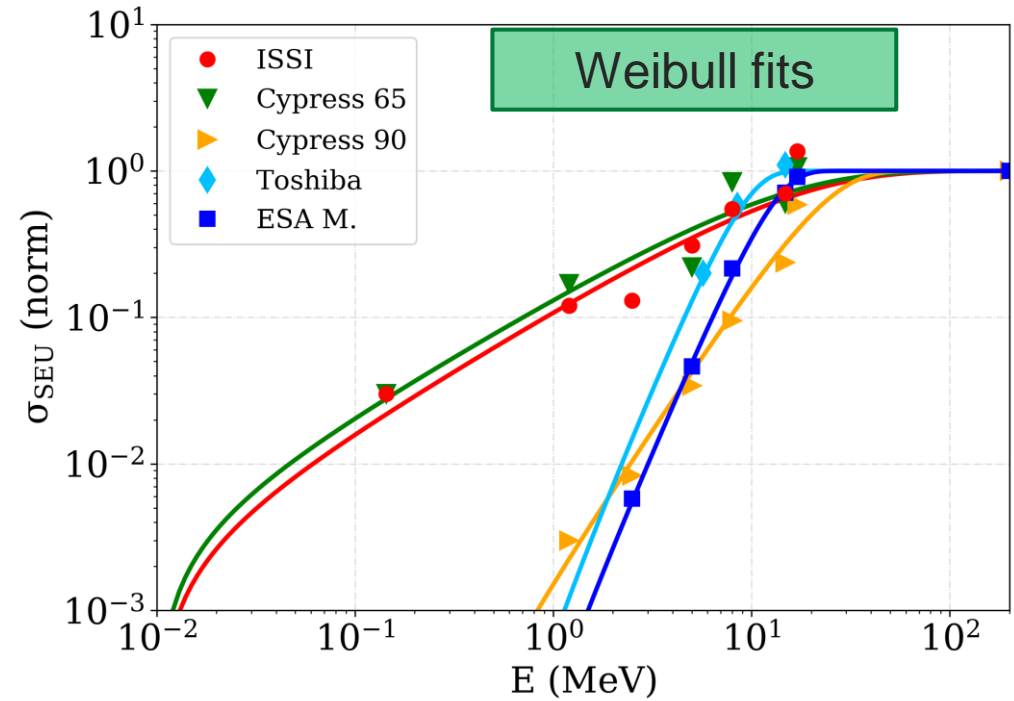
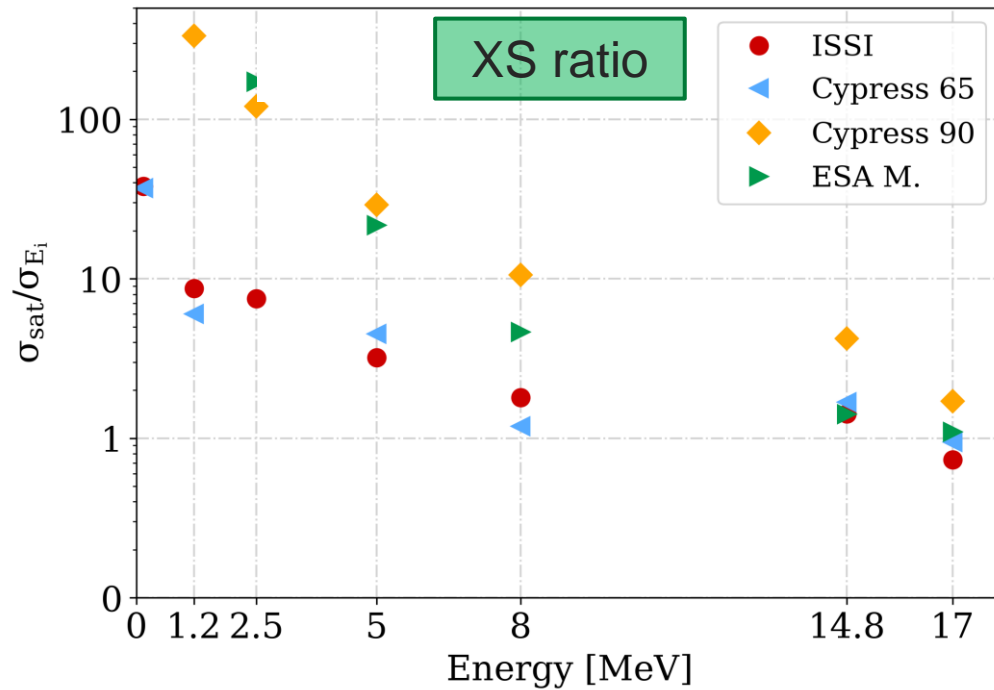
Neutron SEU cross section still very high at low energies!

90 and 250 nm SRAMs

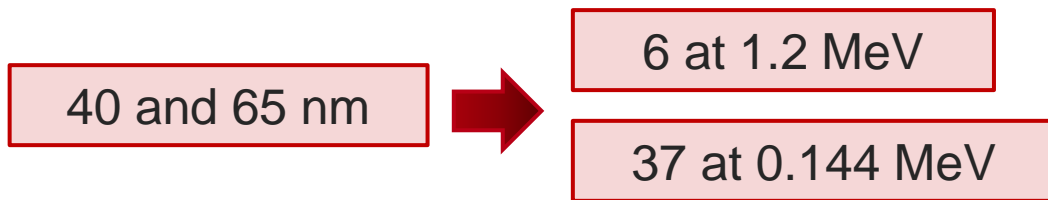
Typical behaviour

No significant difference between package/delidded tests

Cross section comparison to saturated value



- Ratio between high energy proton (saturated) and neutron cross sections of :



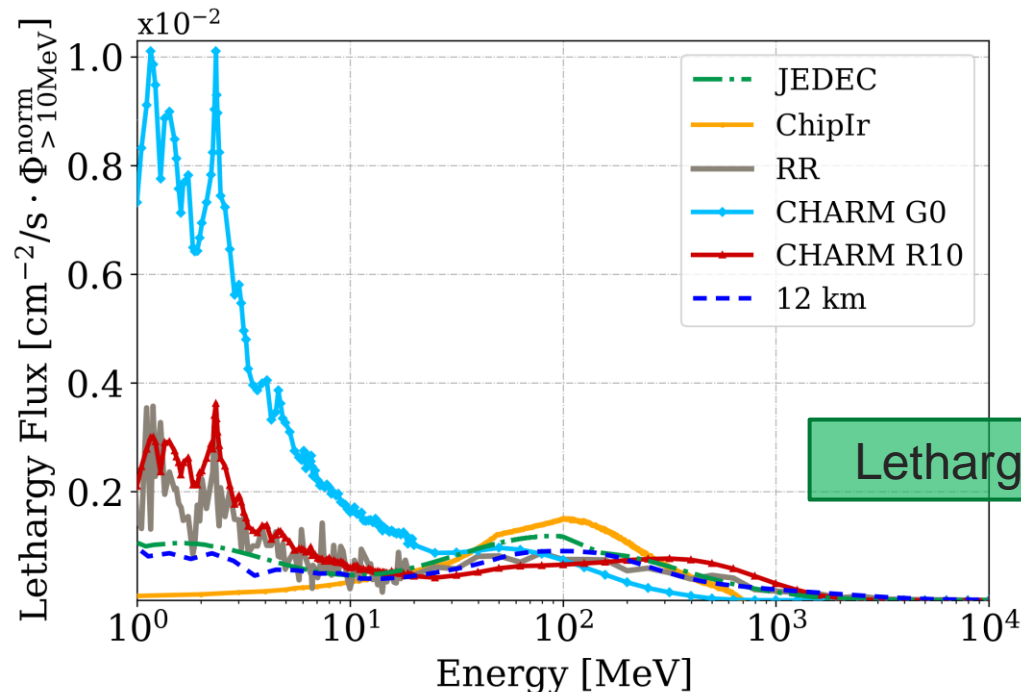
Neutron spectra of different environments

Accelerator

- Hard spectra → RR alcove, R10
- Soft spectrum → G0 - **highest flux below 10 MeV**

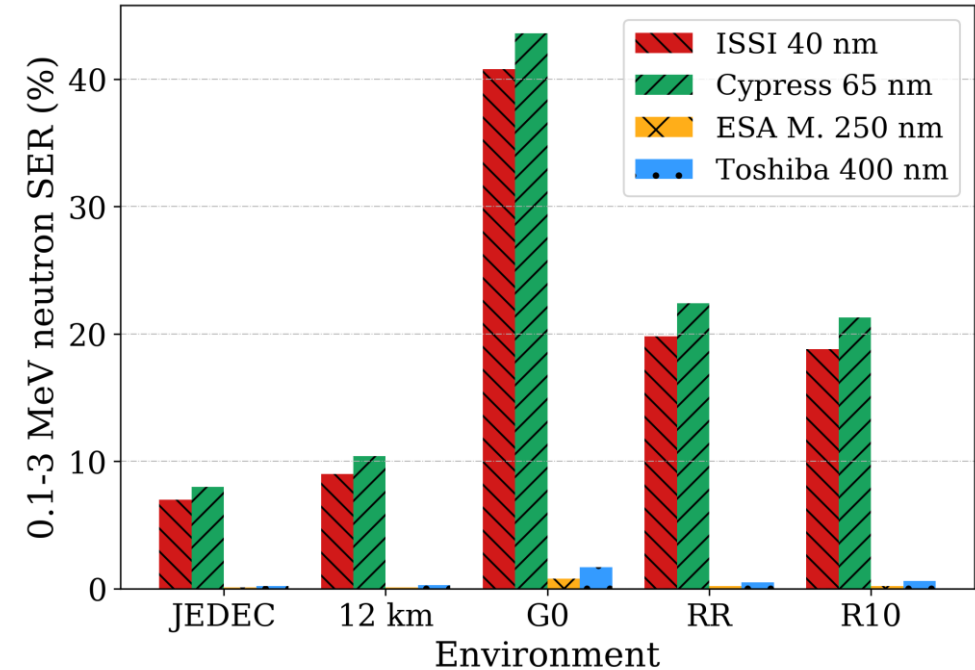
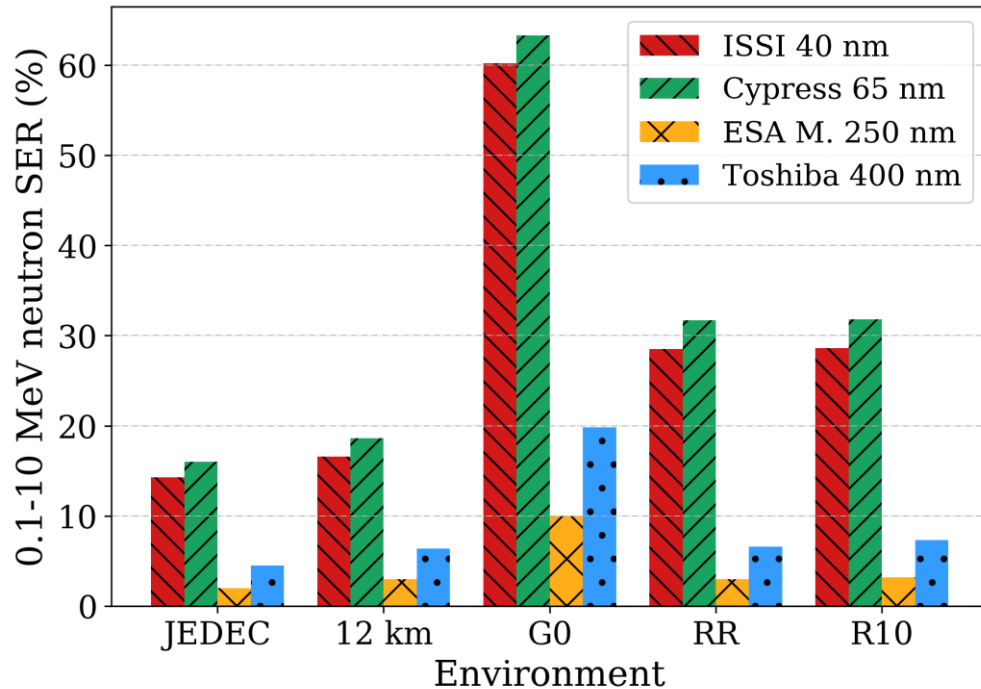
Atmospheric

- Ground level → JEDEC (1 m)
- Avionic → 12 km altitude above Geneva



Spectra normalized to the JEDEC New York City fluence above 10 MeV

SEUs induced by neutrons below 10 MeV on the overall rate



0.1-10 MeV neutrons → Up to 60% of SEUs in accelerator
19% of SEUs in avionics

0.1-3 MeV neutrons → Up to 44% of SEUs in accelerator
10% of SEUs in avionics

- Neutrons **<1 MeV** → **21%** of SEUs in Cypress 65 nm in accelerator
- Negligible contribution below **0.1 MeV**

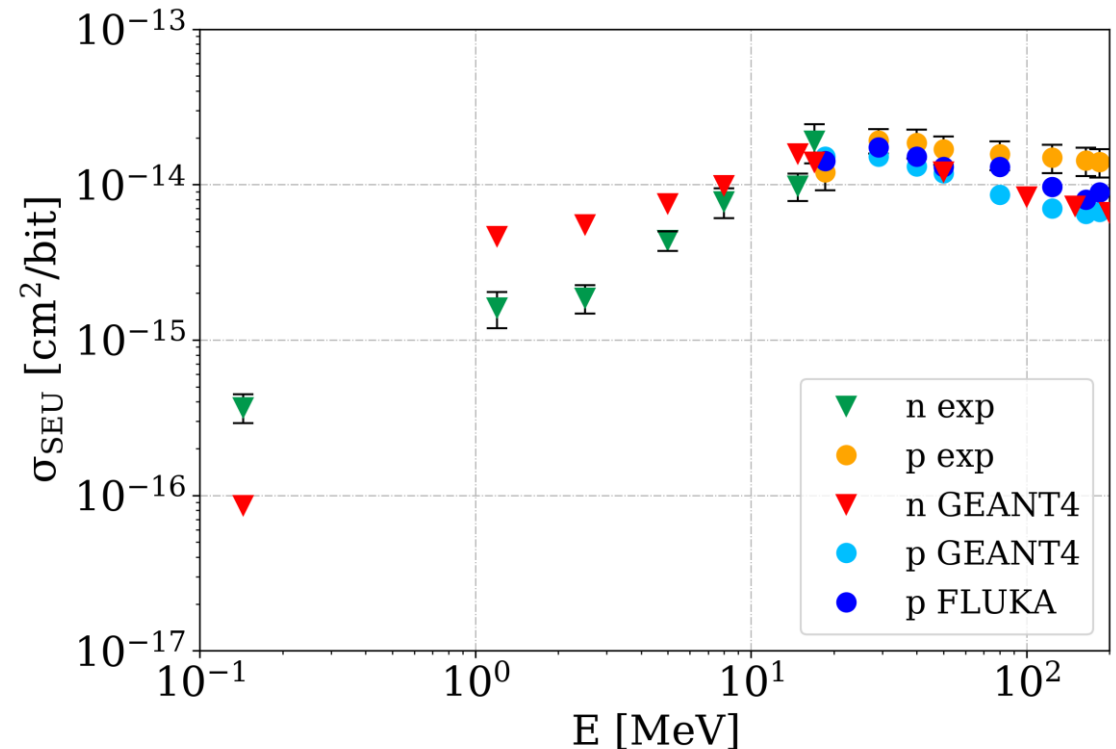
SEU simulations – GEANT4

ISSI 40 nm memory modelled in **GEANT4** (G4SEE, *see David's presentation*) and **FLUKA**

- Si bulk 250 nm sides cubic **RPPs** - SiO₂ **BEOL** of 6 μm - **Qc = 0.72 fC**
- Model benchmarked against proton (18 – 200 MeV) and neutron (0.144 – 17 MeV) experimental data



- **Satisfactory agreement** considering the broad range of energies and particle species
- Simulations confirm **neutrons can deposit enough energy to trigger SEUs even at 0.144 MeV**

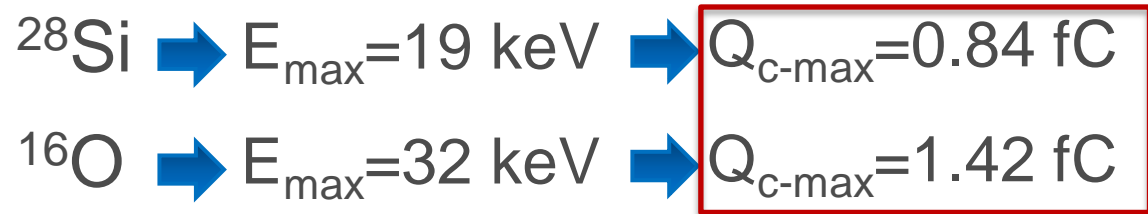


Energy deposition – Elastic vs inelastic processes

- Energy threshold for (n,a) **inelastic interactions** in ^{28}Si is **2.75 MeV**
- Below this threshold mostly **elastic processes** take place

Maximum energy transferred by a neutron (**144 keV**) in elastic reactions:

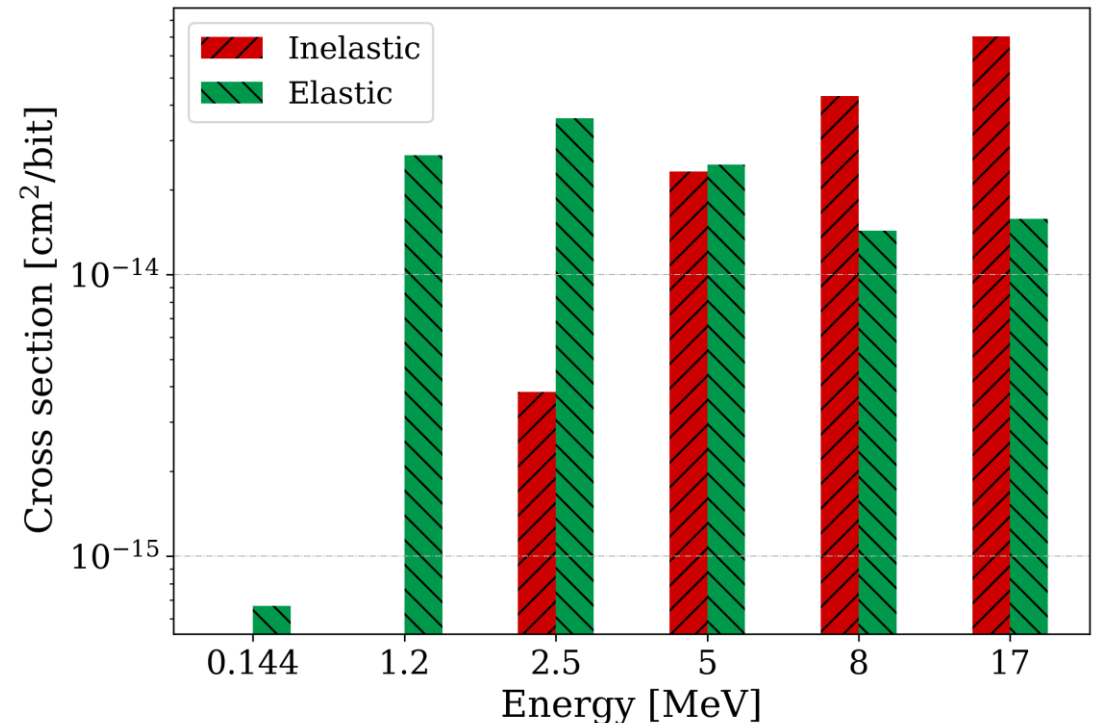
$$E_{max} = E_n \cdot \frac{4A}{(A + 1)^2}$$



Both **above memory Q_c**

More energy transferred to lighter nucleus

→ oxygen



Radiation Hardness Assurance (RHA) implications

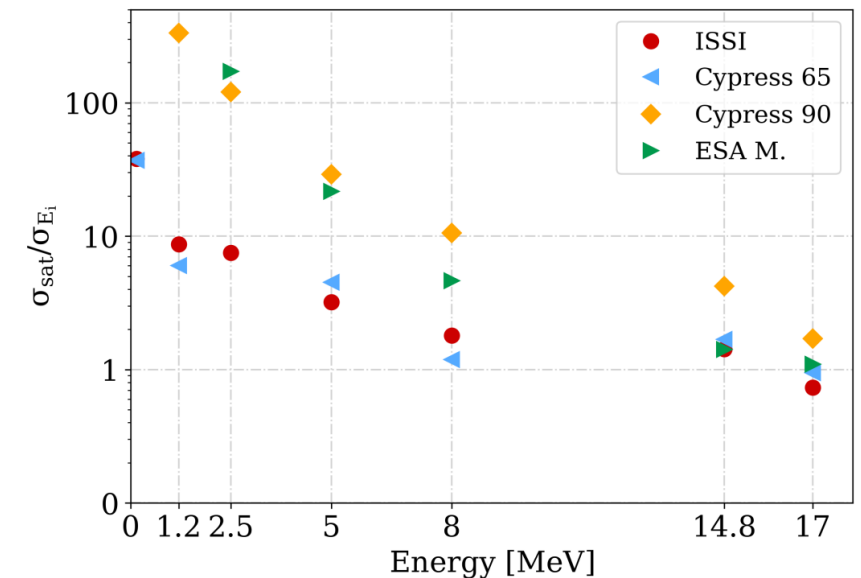
Toshiba reference memory used for the HEHeq fluence calculation not anymore the worst-case response

→ Possible SER underestimations

RHA solutions:

1. **Safety margin** to the HEHeq fluence (at least factor 2)
2. Implement **Cypress 65 nm response** for the HEHeq fluence calculation
3. Component **qualification with 2.5 MeV neutrons** and comparison to saturated cross section

Spectrum	$\frac{\text{HEHeq(Cypress65)}}{\text{HEHeq(Toshiba)}}$		
	<10 MeV	<20 MeV	Full
G0	6.22	3.02	1.95
RR	6.21	2.50	1.29



Conclusions

- In the commercial SRAMs studied in this work, neutrons between 0.1-10 MeV can induce up to:

60% of SEUs in accelerator **19% of SEUs in avionics**

- RHA (for accelerator) → Neutrons between **0.1 – 10 MeV** yield dominating SEU contribution
- Potential treat for **medical** and **fusion** applications
- Toshiba 400 nm response for HEHeq flux not anymore the worst case
- **Elastic processes** can deposit enough energy to trigger SEUs even at 144 keV, as proved experimentally and via simulations

This presentation: M. Cecchetto et Al, “0.1-10 MeV Neutron Soft Error Rate in Accelerator and Atmospheric Environments” IEEE TNS

Thermal neutrons: M. Cecchetto et Al, “Thermal Neutron Induced SEUs in the LHC Accelerator Environment” , IEEE Trans. Nucl. Sci., 2020

Thank you for
your attention!

